

## 17.5 Index of techniques and abbreviations

ADAS	Angular dependent Auger spectroscopy	17.2.4
AEAPS	Auger electron appearance potential spectroscopy	17.2.3
AEES	Auger electron emission spectroscopy	17.2.4
AES	Auger electron spectroscopy	17.2.4
APD	Azimuthal photoelectron diffraction	17.2.1.6
APS	Appearance potential spectroscopy	17.2.3
ARAES	Angle resolved Auger electron spectroscopy	17.2.4
ARUPS	Angle resolved ultraviolet photoelectron spectroscopy	17.2.1.4
ARXPS	Angle resolved X-ray photoelectron spectroscopy	17.2.1.4
ATR	Infrared attenuated total reflection spectroscopy	17.7.5
-	Infrared emission spectroscopy	17.7.5
BIS	Bremsstrahlung isochromat spectroscopy	17.2.2.2
BS	Bremsstrahlung spectroscopy	17.2.2.2
CFSS	Constant final state spectroscopy	17.2.1.4
CISS	Constant initial state spectroscopy	17.2.1.4
CLS	Characteristic loss spectroscopy	17.2.2.1
DAPS	Disappearance potential spectroscopy	17.2.3
DRIFT	Diffuse reflectance infrared spectroscopy	17.7.5
DSPES	Depth selective photoelectron spectroscopy	17.2.1.3
EAAPS	Electron excited Auger electron appearance potential spectroscopy	17.2.3
EAES	Electron excited Auger electron spectroscopy	17.2.4
EAPFS	Extended (or electron) appearance potential fine structure (analysis or spectroscopy)	17.2.3
(ECS)	Electron coincidence spectroscopy	17.2.5
EDCS	Energy distribution curve spectroscopy	17.2.1.4
EDS	Energy distribution spectroscopy	17.2.1.4
EEAES	Electron excited Auger electron spectroscopy	17.2.4
EELFS	Extended energy-loss fine structure (spectroscopy)	17.2.2.1
EELS	Electron energy-loss spectroscopy	17.2.2.1
EIAES	Electron induced Auger electron spectroscopy	17.2.4
EIS	Electron impact spectroscopy	17.2.2
ELS	Electron-loss spectrometry	17.2.2.1
EPMA	Electron probe microanalysis	17.3
EPXMA	Electron probe X-ray microanalysis	17.3
ESCA	Electron spectroscopy for chemical analysis	17.2.1.2
ESD	Electronically stimulated desorption (ESD)	17.7.3
ESR	Electron spin resonance	17.7.6
-	Mössbauer spectroscopy	17.7.6
-	Magnetic methods	17.7.6
ETS	Electron transmission spectroscopy	17.2.2.1
EXAPS	Electron excited X-ray appearance potential spectroscopy	17.2.3
EXELFS	Extended electron-energy-loss fine structure (spectroscopy)	17.2.2.1
FEEDS	Field emission energy distribution (spectroscopy)	17.2.7

FES	Field emission spectroscopy	17.2.7
FIM	Field ion microscopy	17.3
FIMS	Field ionisation mass spectrometry	17.7.3
HEELS	High energy electron energy loss spectroscopy	17.2.2.1
-	Helium diffraction	17.7.3
HREELS	High resolution electron energy loss spectroscopy	17.2.2.1
IAES	Ion excited Auger electron spectroscopy	17.2.4
IEMM	Incident energy modulation method (spectroscopy)	17.2.3
IETS	Inelastic electron tunnelling spectroscopy	17.2.5
ILS	Inelastic atom scattering	17.7.5
-	Inelastic neutron scattering	7.7.5
ILS	Ionization loss spectroscopy	17.2.2.1
IM	Ion microscopy	17.3
INS	Ion neutralization spectroscopy	17.2.6
IPMA	Ion probe microanalysis	17.3
IPS	Inverse photoemission spectroscopy	17.2.2.2
IR	Infrared spectroscopy	17.7.5
RS	Raman spectroscopy	17.7.5
-	Infrared transmission spectroscopy	17.7.5
IS	Ionization spectroscopy	17.2.2.1
ISS	Ion scattering spectrometry	17.3
LAMES	Laser micro emission spectroscopy	17.3
LAMMA	Laser microprobe mass analysis	17.3
LEED	Low energy electron diffraction	17.3
MAS	Magic angle spinning method	17.7.6
MQES	Metastable quenched electron spectroscopy	17.2.6
NMR	Nuclear magnetic resonance (for solids)	17.7.6
NPD	Normal photoelectron diffraction	17.2.1.6
PAS	Infrared photoacoustic spectroscopy	17.7.5
PED	Photoelectron diffraction	17.2.1.6
PESM	Photoelectron spectromicroscopy	17.2.1.5
PEYS	Photoelectron yield spectroscopy	17.2.1.4
PESIS	Photoelectron spectroscopy of the inner shell	17.2.1.2
PIXES	Particle induced X-ray emission spectroscopy	17.3
PYS	Partial yield spectroscopy	17.2.1.4
RAIRS	Reflection-absorption infrared spectroscopy	17.7.5
-	Infrared ellipsometric spectroscopy	17.7.5
(REPS)	Resonance enhanced photoelectron spectroscopy	17.2.1.4
RBS	Rutherford backscattering	17.3
RHEED	Reflection high energy electron diffraction	17.3
SAM	Scanning Auger microscopy	17.2.4
SEM	Scanning electron microscopy	17.3
SESCA	Scanning electron spectroscopy for chemical applications	17.2.1.5
SEXAFS	Surface extended X-ray absorption fine structure (spectroscopy)	17.2.1.4
SIMS	Secondary ion mass spectrometry	17.3

SPAES	Spin polarized Auger electron spectroscopy	17.2.4
SPIES	Surface penning ionization electron spectroscopy	17.2.6
SRPES	Synchrotron radiation photoelectron spectroscopy	17.2.1.4
STEM	Scanning transmission electron microscopy	17.3
STM	Scanning tunnelling microscopy	17.7.3
SXAPS	Soft X-ray appearance potential spectroscopy	17.2.3
SXPS	Soft X-ray photoelectron spectroscopy	17.2.1.2
TCS	Total current spectroscopy	17.2.3
TEM	Transmission electron microscopy	17.3
THEED	Transmission high energy electron diffraction	17.3
TPD	Thermal desorption spectroscopy	17.3
UPES	Ultraviolet photoelectron spectroscopy	17.2.1.1
XAES	X-ray excited Auger electron spectroscopy	17.2.4
XAPS	X-ray appearance potential spectroscopy	17.2.3
XEAES	X-ray excited Auger electron spectroscopy	17.2.4
XEAPS	X-ray excited electron appearance potential spectroscopy	17.2.3
XPES	X-ray photoelectron (or photoemission) spectroscopy	17.2.1.2
XRD	X-ray diffraction (in situ, micro)	17.3